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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/607,912	06/27/2003	Bernard Andre	BREV 13186 DIV	8153
7590 Norman P. Soloway HAYES SOLOWAY P.C. 130 W. Cushing Street Tucson, AZ 85701		02/22/2007	EXAMINER STOUFFER, KELLY M	
			ART UNIT 1762	PAPER NUMBER
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Serial No. : 10/607,912

Applicant : Bernard et al.

Filing Date : June 27, 2003

Date Mailed : February 21, 2007

## ACKNOWLEDGEMENT OF REQUEST

### *Notice of Allowance/Allowability Mailed*

The request for a copy of the initialed PTO 1449, dated June 19, 2006, has been received by the U.S. Patent and Trademark Office.

- Requested copy attached

A. Marty Willis  
For the Office of Patent Publication

<b>Notice of References Cited</b>		Application/Control No. 09/830,380	Applicant(s)/Patent Under Reexamination ANDRE ET AL.	
		Examiner Tamra L. Dicus	Art Unit 1774	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
✓	A	US-5,399,435	03-1995	Ando et al.	428/428
✓	B	US-5,623,375	04-1997	Floch et al.	359/871
✓	C	US-5,691,044	11-1997	Oyama et al.	313/461
	D	US-			
	E	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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3/26/05

Examiner

Wes March

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<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>		Docket Number (Optional) <b>BREV 13186</b>	Application Number
		Applicant(s) <b>ANDRE et al</b>	
		Filing Date <b>APRIL 25, 2001</b>	Group Art Unit
		*EXAMINER INITIAL <i>WA</i>	OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>
	<p>"Optical Coatings Deposited by Reactive Ion Plating" by A.J. Waldorf et al Applied Optics/October 1, 1993/Vol. 32, No. 28 pgs. 5583-5593</p> <p>"Optical Coatings for High-Power Neodymium Lasers" by B. Brauns et al Sov. J. Quantum Electron. 18 (10) Oct. 1988, c 1989 American Institute of Physics pgs. 1286-1290</p> <p>"Investigation of Optical Damage Mechanisms in Hafnia and Silica Thin Films Using Pairs of Subnanosecond Laser Pulses with Variable Time Delay" by L.L. Chase, et al J. Appl. Phys. 71 (3) February 1, 1992/American Institute of Physics pgs. 1204-1208</p> <p>"Characterization of Defect Geometries in Multilayer Optical Coatings" by R.J. Tench et al J. Vac. Sci. Technol. A 12(5), Sep/Oct 1994 1994 American Vacuum Society pgs. 2808-2813</p> <p>"Reactive Evaporation of Low-Defect Density Hafnia" by R.Chow et al Applied Optics/ October 1, 1993/ Vol. 32, No. 28/ pgs. 5567-5574</p> <p>"Stress and Environmental Shift Characteristics of HfO<sub>2</sub>/Si<sub>2</sub> Multilayer Coatings" by J.F. Anzellotti et al Proceedings Reprint/SPIE - The International Society for Optical Engineering Reprinted From 28th Annual Boulder Damage Symposiumproceedings "Laser-Induced Damage in Optical Materials: 1996" October 7-9, 1996, Boulder, Colorado SPIE Vol. 2966, pgs. 258-264</p> <p>"Study of the Structure and Properties of Thick Vacuum Condensates of Nickel, Titanium, Tungsten, Aluminum Oxide and Zirconium Dioxide" by B.A. Movchan et al F metal.metallized., 28, No. 4, 653-660, 1969 pgs. 83-90</p> <p>"Nano Absorbing Centers: A Key Point in Laser Damage of Thin Films" by J. Dijon et al SPIE Vol. 2966, pgs 315-325</p>		
EXAMINER <i>WA</i>	DATE CONSIDERED <i>3-24/05</i>		

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